

March 1996



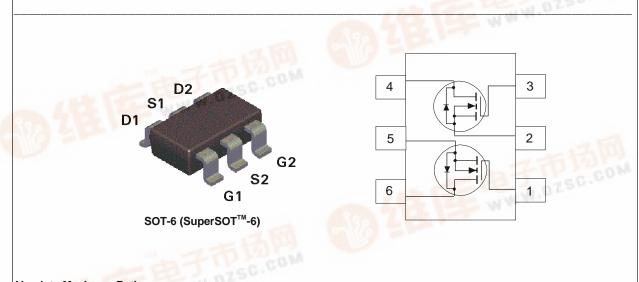
NDC7002N Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

These dual N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process has been designed to minimize on-state resistance, provide rugged and reliable performance and fast switching. These devices is particularly suited for low voltage applications requiring a low current high side switch.

Features

- 0.51A, 50V, $R_{DS(ON)} = 2\Omega @ V_{GS} = 10V$
- High density cell design for low R_{DS(ON)}.
- Proprietary SuperSOT[™]-6 package design using copper lead frame for superior thermal and electrical capabilities.
- High saturation current.



Absolute	Maximum Ratings T _A = 25°C unless otherwise	se noted		
Symbol	Parameter		NDC7002N	Units
V _{DSS}	Drain-Source Voltage		50	V
V _{GSS}	Gate-Source Voltage - Continuous		20	V
I _D	Drain Current - Continuous	(Note 1a)	0.51	Α
	- Pulsed		1.5	
P _D	Maximum Power Dissipation	(Note 1a)	0.96	W
	- 13	(Note 1b)	0.9	
	~ 7 TD 14	(Note 1c)	0.7	
T_J,T _{STG}	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS	•		
R _{øja}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	130	°C/W
R _{ØJC}	Thermal Resistance, Junction-to-Case	(Note 1)	60	°C/W

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	ARACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		50			V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{\rm DS} = 40 \text{ V}, V_{\rm GS} = 0 \text{ V}$				1	μA
			T _J = 125°C			500	
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHA	RACTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 250 \ \mu {\rm A}$		1	1.9	2.5	V
			T _J = 125°C	0.8	1.5	2.2	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 0.51 \text{ A}$			1	2	Ω
			T _J = 125°C		1.7	3.5	
		$V_{GS} = 4.5 \text{ V}, \ I_{D} = 0.35 \text{ A}$			1.6	4	
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$		1.5			Α
9 _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 0.51 \text{ A}$			400		mS
DYNAMI	C CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			20		pF
C _{oss}	Output Capacitance				13		pF
C _{rss}	Reverse Transfer Capacitance				5		pF
SWITCHI	NG CHARACTERISTICS (Note 2)						
t _{D(on)}	Turn - On Delay Time	$V_{\rm DD} = 25 \text{ V}, \ \text{I}_{\rm D} = 0.25 \text{ A}, \\ V_{\rm GS} = 10 \text{ V}, \ \text{R}_{\rm GEN} = 25 \ \Omega$			6	20	nS
t _r	Turn - On Rise Time				6	20	
t _{D(off)}	Turn - Off Delay Time				11	20	
t _f	Turn - Off Fall Time				5	20	
Q _q	Total Gate Charge	$V_{DS} = 25 V,$ $I_{D} = 0.51 A, V_{GS} = 10 V$			1		nC
Q _{gs}	Gate-Source Charge				0.19		nC
Q _{gd}	Gate-Drain Charge				0.33		nC

ELECTRICAL CHARACTERISTICS (T _A = 25°C unless otherwise noted)						
Symbol	Parameter	Conditions	Min	Тур	Max	Units
DRAIN-SOURCE DIODE CHARACTERISTICS						
I _s	Maximum Continuous Source Current				0.51	А
I _{SM}	Maximum Pulse Source Current (Note 2)				1.5	А
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{S} = 0.51 \text{ A} (Note 2)$		0.8	1.2	V

Notes:

1. R_{gut} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{gut} is guaranteed by design while R_{got} is determined by the user's board design.

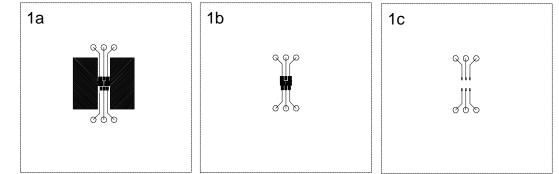
$$P_D(t) = \frac{T_J - T_A}{R_{BJ}(\delta t)} = \frac{T_J - T_A}{R_{BJ}(\delta T_B) c_A(t)} = I_D^2(t) \times R_{DS(ON)} \theta_{TJ}$$

Typical $R_{_{BJA}}$ for single device operation using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

a. 130°C/W when mounted on a 0.125 in² pad of 2oz cpper.

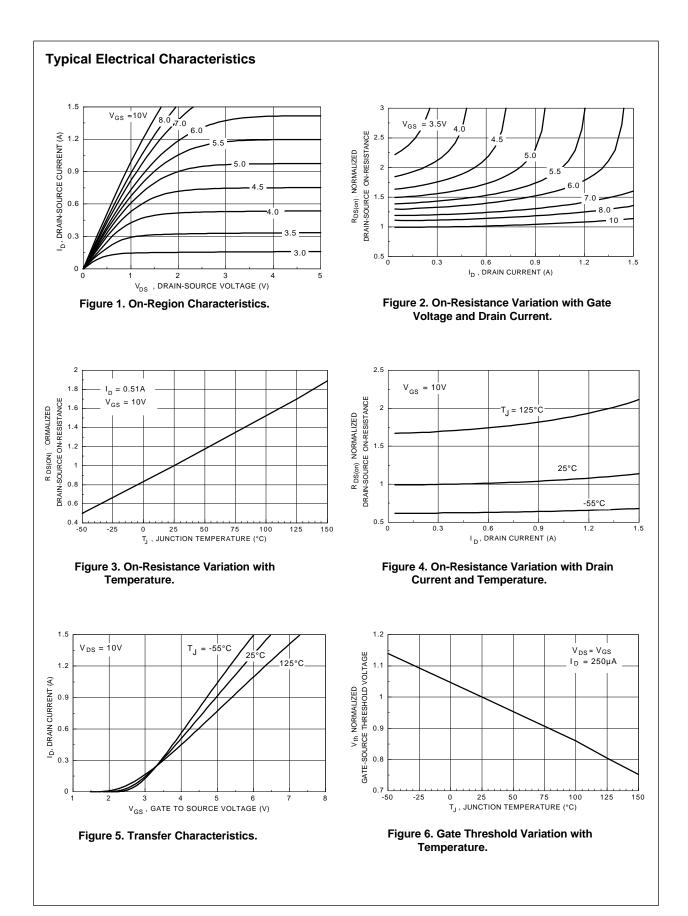
b. 140°C/W when mounted on a 0.005 \mbox{in}^2 pad of 2oz cpper.

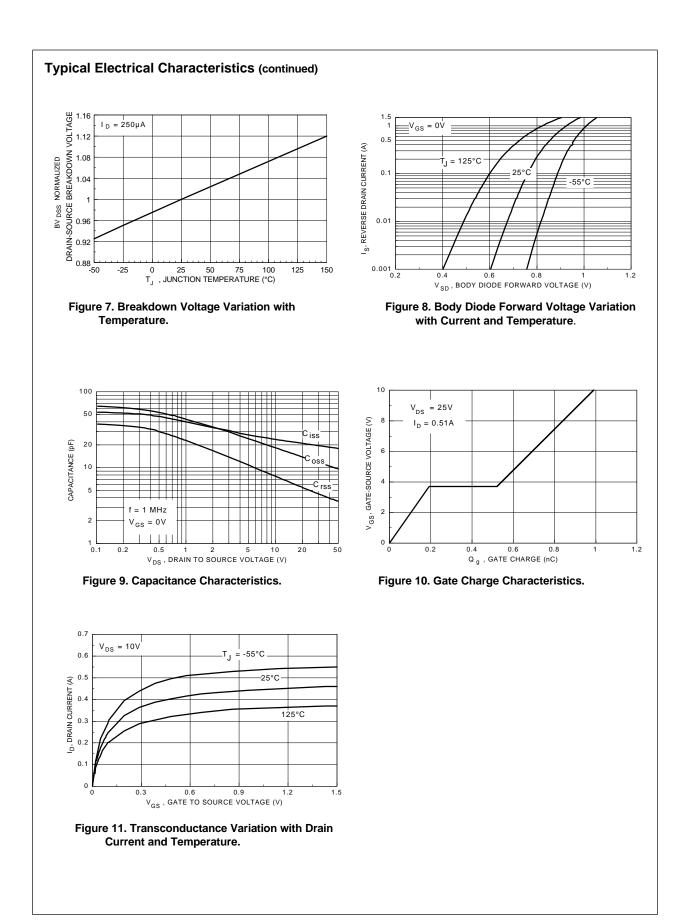
c. 180°C/W when mounted on a 0.0015 \mbox{in}^2 pad of 2oz cpper.

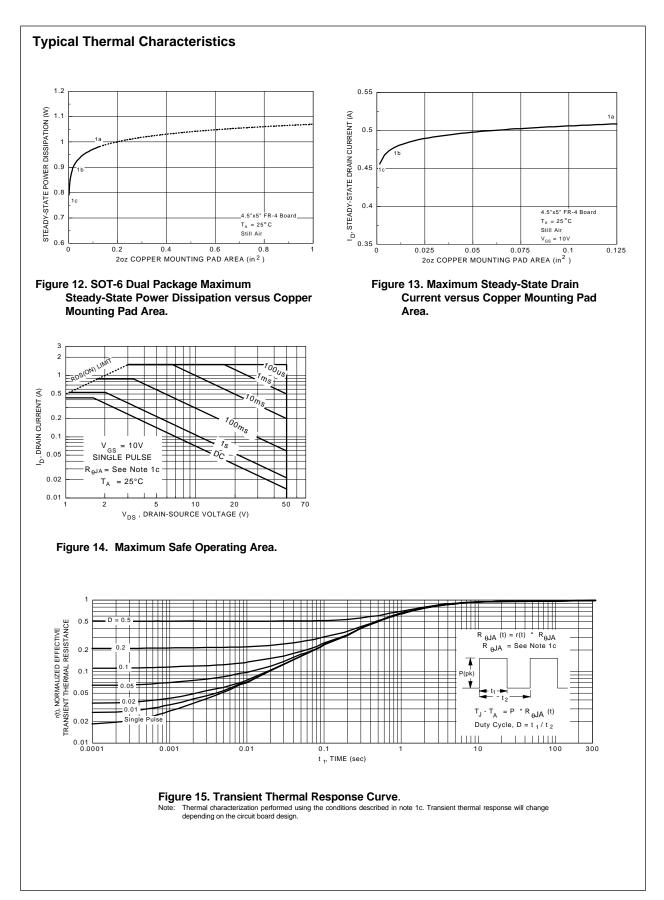


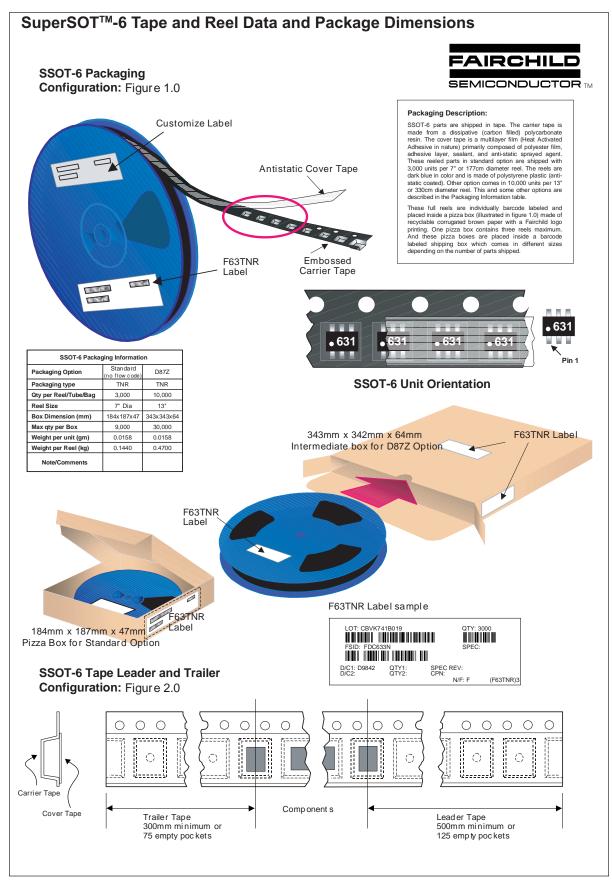
Scale 1 : 1 on letter size paper

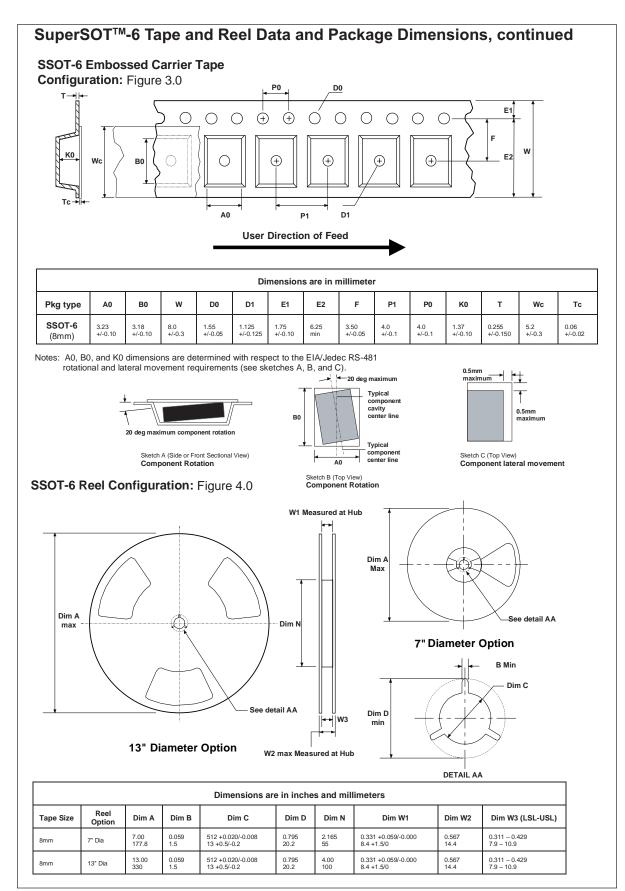
2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.

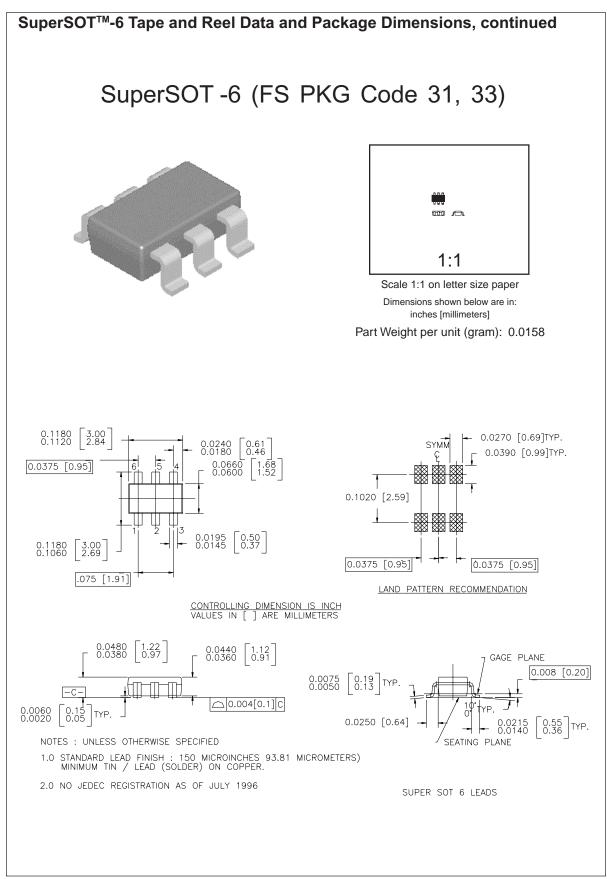












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